

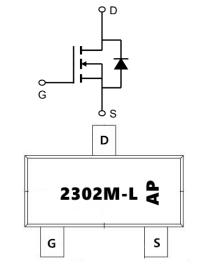
#### **Description**

The AP2302MI-L uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

#### **General Features**

 $V_{DS} = 20V I_{D} = 3.5A$ 

 $R_{DS(ON)} < 52m\Omega$  @  $V_{GS}=10V$  (Type: 46m $\Omega$ )



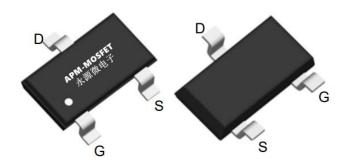
Top View Bottom View

**Application** 

Battery protection

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

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Product ID	Pack	Marking	Qty(PCS)
AP2302MI-L	SOT23-3L	2302M-L-AP	3000

#### Absolute Maximum Ratings (T<sub>C</sub>=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units
V <sub>D</sub> s	Drain-Source Voltage	20	V
Vgs	Gate-Source Voltage	±12	V
I <sub>D</sub> @T <sub>A</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ 4.5V <sup>1</sup>	3.5	А
I <sub>D</sub> @T <sub>A</sub> =70°C	Continuous Drain Current, V <sub>GS</sub> @ 4.5V <sup>1</sup>	2.3	А
Ірм	Pulsed Drain Current <sup>2</sup>	10.6	А
P <sub>D</sub> @T <sub>A</sub> =25°C	Total Power Dissipation <sup>3</sup>	1	W
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
RθJA	Thermal Resistance Junction-ambient <sup>1</sup>	125	°C/W
Rejc	Thermal Resistance Junction-Case <sup>1</sup>	80	°C/W





#### Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	20	22		V
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =4.5V , I <sub>D</sub> =3A		46	52	mΩ
		V <sub>GS</sub> =2.5V , I <sub>D</sub> =2A		55	65	
VGS(th)	Gate Threshold Voltage	$V_{GS}$ = $V_{DS}$ , $I_D$ =250uA	0.4	0.6	1.2	V
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =16V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	uA
IDSS		V <sub>DS</sub> =16V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C			5	
IGSS	Gate-Source Leakage Current	V <sub>GS</sub> =±12V , V <sub>DS</sub> =0V			±100	nA
gfs	Forward Transconductance	$V_{DS}$ =5 $V$ , $I_{D}$ =3 $A$		10.5		S
Qg	Total Gate Charge (4.5V)			4.6		
Qgs	Gate-Source Charge	V <sub>DS</sub> =15V , V <sub>GS</sub> =4.5V , I <sub>D</sub> =3A		0.7		nC
Qgd	Gate-Drain Charge			1.5		
Td(on)	Turn-On Delay Time			1.6		
Tr	Rise Time	V <sub>DD</sub> =10V , V <sub>GS</sub> =4.5V ,		42		
Td(off)	Turn-Off Delay Time	$R_G$ =3.3Ω $I_D$ =3A		14		ns
Tf	Fall Time			7		
Ciss	Input Capacitance			310		
Coss	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , f=1MHz		49		pF
Crss	Reverse Transfer Capacitance			35		1
IS	Continuous Source Current <sup>1,4</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			3.6	Α
VSD	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C			1.2	V

#### Note:

- 1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2. The data tested by pulsed , pulse width  $\leq 300 \text{us}$  , duty cycle  $\leq 2\%$
- $3\ensuremath{^{\circ}}$  The power dissipation is limited by  $150\ensuremath{^{\circ}}\!\ensuremath{^{\circ}}$  junction temperature
- $4\sqrt{1}$  The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.



#### **Typical Characteristics**

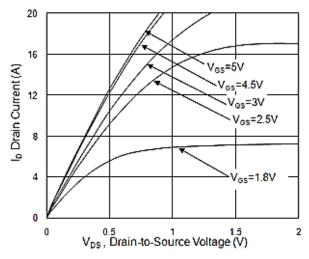
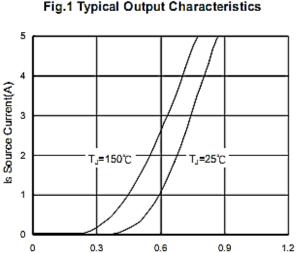


Fig.1 Typical Output Characteristics



V<sub>SD</sub>, Source-to-Drain Voltage (V)

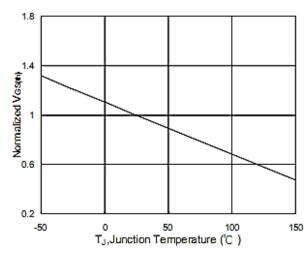


Fig.5 Normalized V<sub>GS(th)</sub> vs. T<sub>J</sub>

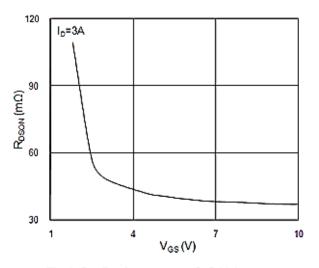
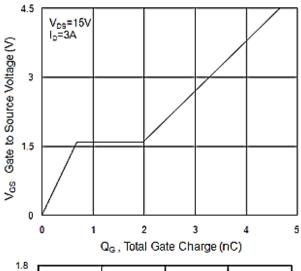


Fig.2 On-Resistance vs. G-S Voltage



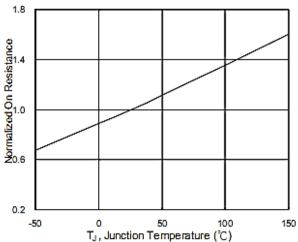
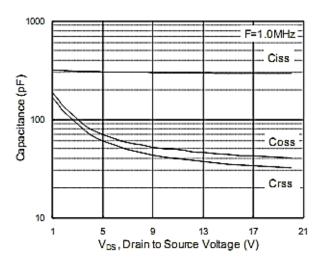


Fig.6 Normalized RDSON vs. TJ







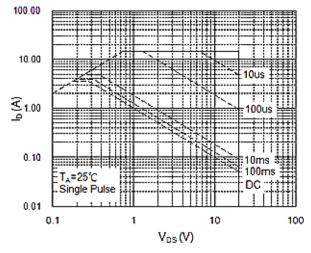


Fig.7 Capacitance

Fig.8 Safe Operating Area

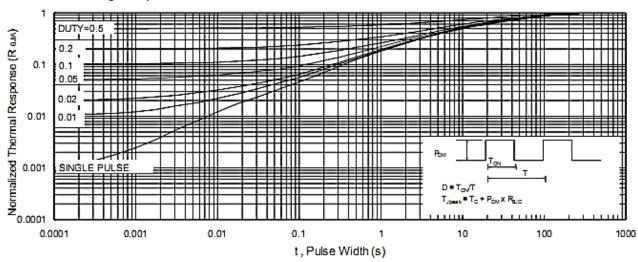
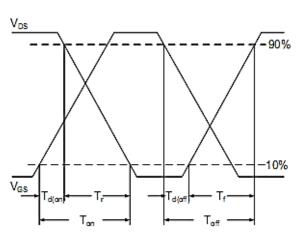


Fig.9 Normalized Maximum Transient Thermal Impedance



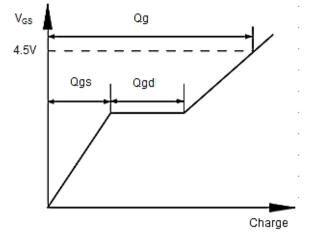
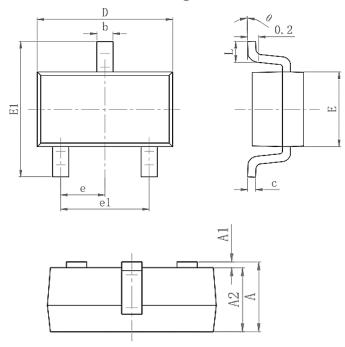


Fig.10 Switching Time Waveform

Fig.11 Gate Charge Waveform



# Package Mechanical Data-SOT23-3L-Single



	Dimensions in	n Millimeters
Symbol	mı	m
	Min	Max
Α	1.05	1.25
A1	0.000	0.100
A2	1.05	1.15
b	0.25	0.45
С	0.100	0.200
D	2.820	3.020
E	1.500	1.700
E1	2.650	2.950
е	0.950 (	BSC)
e1	1.800	2.000
L	0.300	0.500
θ	0°	8°



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# AP2302MI-L

## **20V N-Channel Enhancement Mode MOSFET**

Edition	Date	Change
REV1.0	2020/5/1	Initial release

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